

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: A1412-02 DA	ATE: December 23, 2014	MEANS OF D	DISTINGUISHING CHANGED DEVICES:		
Product Affected: PBGA-256, 313, 376 TEPBGA-420, 480 (Refer Attachment II for affected part#) Date Effective: March 23, 2015		 Product Mark Assembly lot marked on the device Back Mark provides traceability to the material Date Code used Other 			
Contact: IDT PCN DESK		Attachment:	Yes 🗌 No		
E-mail: <u>pcndesk@idt.com</u>			ontact your local sales representative for mple and datasheet requests.		
DESCRIPTION AND PURPOSE OF	CHANGE:				
 Die Technology Wafer Fabrication Process Assembly Process This notification is to inform our customers that IDT is converting to a new mold compound, Hitachi CEL-9750ZHF10AKL. 					
EquipmentMaterial	There is no change in the	e moisture sensi	tivity level (MSL).		
 Testing Manufacturing Site Data Sheet Other 	ngAttachment I: Details of change.facturing SiteAttachment II: Affected part list.SheetSheet				
RELIABILITY/QUALIFICATION SUMMARY: There is no expected change to the product quality or reliability performance. Refer to attachments for Qualification data.					
	written notification of this c information. If IDT does n cceptable. ersion manufactured after th	ot receive ackn	ase the acknowledgement below or E-Mail owledgement within 90 days of this notice ge effective date until the inventory		
Customer:		Approva	l for shipments prior to effective date.		
Name/Date:	E-M	Mail Address:			
Title:	Pho	one# /Fax# :			
CUSTOMER COMMENTS:					
IDT ACKNOWLEDGMENT OF RE	CCEIPT:				
RECD. BY:		DATE:			



Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

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ATTACHMENT I - PCN # : A1412-02

PCN Type:	Assembly Material
Data Sheet Change:	None
Details Of Change:	This notification is to inform our customers that IDT is converting to a new mold compound, Hitachi CEL-9750ZHF10AKL.
	There is no change in the moisture sensitivity level (MSL).

You may contact your local sales representative to acknowledge this PCN and request samples.

Description	Changes		
Description	From	То	
Mold Compound	Hitachi CEL- 9750HF10F	Hitachi CEL- 9750ZHF10AKL	

Qualification Test Plan and Results:

Test Vehicle: TEPBGA-480 (2 lots) and PBGA-313 (1 lot)

		Test R	esults (S	5 / Rej)
Test Description	Test Method	Lot 1	Lot 2	Lot 3
 * Highly Accelerated Stress Test (Unbiased, 130°C/85% RH, 96Hrs) 	JESD22-A118	30/0	30/0	30/0
* Temperature Cycle / Condition B (-55 °C to +125 °C, 700 Cyc)	JESD22-A104	30/0	30/0	30/0
High Temp. Storage Test (150 °C, 1000 Hrs)	JESD22-A103	30/0	30/0	30/0
Ball Shear Test	JESD22-B116	5/0	5/0	5/0
X-ray Examination	IDT Spec. MAC-3012 (Package voids, Die attach voids and Wire sweep)	45/0	45/0	45/0

Note:

* Test requires moisture pre-conditioning sequence per JESD22-A113 prior to stress test



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ATTACHMENT II - PCN # : A1412-02

Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
CA91C142D-25EE	CA91L750-100ILV	CA91L8260B-100IEV	TSI350A-66CLV
CA91C142D-33CE	CA91L8200B-100CE	CA91L862A-50IE	TSI384-133IL
CA91C142D-33CEV	CA91L8200B-100IE	CA91L862A-50IEV	TSI384-133ILV
CA91C142D-33IE	CA91L8260B-100CE	CA91L862A-50IL	
CA91C142D-33IEV	CA91L8260B-100CEV	CA91L862A-50ILV	